

Nicolas J-H Roche

List of Publications by Year in descending order

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#	ARTICLE	IF	CITATIONS
1	Investigation of Single-Event Transients in AlGaIn/GaN MIS-Gate HEMTs Using a Focused X-Ray Beam. IEEE Transactions on Nuclear Science, 2019, 66, 368-375.	2.0	9
2	Correlation of the Spatial Variation of Single-Event Transient Sensitivity With Thermoreflectance Thermography in $\text{Al}_{1-x}\text{Ga}_x\text{N}/\text{GaN}$ HEMTs. IEEE Transactions on Nuclear Science, 2018, 65, 369-375.	2.0	6
3	Atypical Effect of Displacement Damage on LM124 Bipolar Integrated Circuits. IEEE Transactions on Nuclear Science, 2018, 65, 71-77.	2.0	2
4	Application of a Focused, Pulsed X-Ray Beam to the Investigation of Single-Event Transients in $\text{Al}_{0.3}\text{Ga}_{0.7}\text{N}/\text{GaN}$ HEMTs. IEEE Transactions on Nuclear Science, 2017, 64, 97-105.	2.0	9
5	Single-Event Effects in High-Frequency Linear Amplifiers: Experiment and Analysis. IEEE Transactions on Nuclear Science, 2017, 64, 125-132.	2.0	5
6	Single-Event Effects in a Millimeter-Wave Receiver Front-End Implemented in 90 nm, 300 GHz SiGe HBT Technology. IEEE Transactions on Nuclear Science, 2017, 64, 536-543.	2.0	5
7	An Investigation of Single-Event Effect Modeling Techniques for a SiGe RF Low-Noise Amplifier. IEEE Transactions on Nuclear Science, 2016, 63, 273-280.	2.0	16
8	Single-Event Effects in a W-Band (75-110 GHz) Radar Down-Conversion Mixer Implemented in 90 nm, 300 GHz SiGe HBT Technology. IEEE Transactions on Nuclear Science, 2015, 62, 2657-2665.	2.0	12
9	Application of a Pulsed Laser to Identify a Single-Event Latchup Precursor. IEEE Transactions on Nuclear Science, 2015, 62, 2679-2686.	2.0	7
10	A Dosimetry Methodology for Two-Photon Absorption Induced Single-Event Effects Measurements. IEEE Transactions on Nuclear Science, 2014, 61, 3416-3423.	2.0	30
11	Impact of Neutron-Induced Displacement Damage & new line; on the ATREE Response in LM124 & new line; Operational Amplifier. IEEE Transactions on Nuclear Science, 2014, 61, 3043-3049.	2.0	7
12	Study and Modeling of the Impact of TID on the ATREE Response in LM124 Operational Amplifier. IEEE Transactions on Nuclear Science, 2014, 61, 1603-1610.	2.0	13
13	Modeling and Investigations on TID-ASETs Synergistic Effect in LM124 Operational Amplifier From Three Different Manufacturers. IEEE Transactions on Nuclear Science, 2013, 60, 4430-4438.	2.0	26
14	An Investigation of Single Event Transient Response in 45-nm and 32-nm SOI RF-CMOS Devices and Circuits. IEEE Transactions on Nuclear Science, 2013, 60, 4405-4411.	2.0	18